

<b>Notice of References Cited</b>	Application/Control No. 10/565,150		Applicant(s)/Patent Under Reexamination JEDELOO, PIETER WILLEM	
	Examiner PING Y. HSIEH		Art Unit 2618	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0008693 A1	01-2003	Tanaka et al.	455/575
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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#### FOREIGN PATENT DOCUMENTS

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